

Notice of References Cited

Application/Control No.

09/767,514

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

3679

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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